



FQB19N20 / FQI19N20

200V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply, DC-AC converters for uninterrupted power supply, motor control.

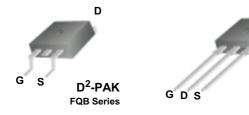
Features

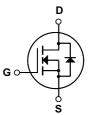
- 19.4A, 200V, $R_{DS(on)} = 0.15\Omega @V_{GS} = 10 V$
- Low gate charge (typical 31 nC)
- Low Crss (typical 30 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- RoHS Compliant

I²-PAK

FQI Series







Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB19N20 / FQI19N20	Units	
V _{DSS}	Drain-Source Voltage		200	V	
I _D	Drain Current - Continuous (T _C = 25°C)		19.4	Α	
	- Continuous (T _C = 100°C)		12.3	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	78	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	250	mJ	
I _{AR}	Avalanche Current	(Note 1)	19.4	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	14	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P _D	Power Dissipation (T _A = 25°C) *		3.13	W	
	Power Dissipation (T _C = 25°C)		140	W	
	- Derate above 25°C		1.12	W/°C	
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.89	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA				V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.18		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 160 V, T _C = 125°C		-	10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V		-	-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 9.7 A		0.12	0.15	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 9.7 A (Note 4)		14.5		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		1220 220 30	1600 290 40	pF pF pF
	ing Characteristics			30	40	рі
t _{d(on)}	Turn-On Delay Time	V _{DD} = 100 V, I _D = 19.4 A,		20	50	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		190	390	ns
t _{d(off)}	Turn-Off Delay Time			55	120	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		80	170	ns
Qg	Total Gate Charge	V _{DS} = 160 V, I _D = 19.4 A,		31	40	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		8.6		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		13.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				19.4	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Forward Current		1	78	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 19.4 A		-	1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 19.4 A,		140		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.69		μC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.0mH, I_{AS} = 19.4A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} \leq 19.4A, di/dt \leq 300A/μs, V_{DD} \leq BV_{DS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300μs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

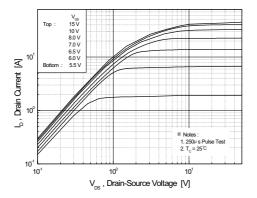


Figure 1. On-Region Characteristics

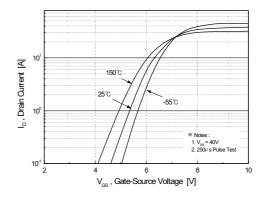


Figure 2. Transfer Characteristics

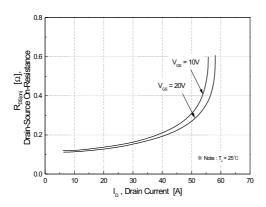


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

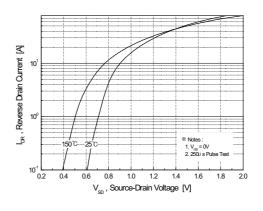


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

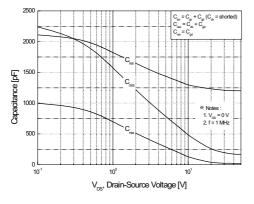


Figure 5. Capacitance Characteristics

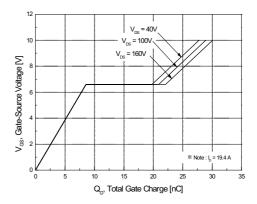


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

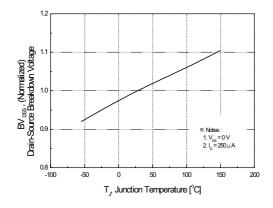
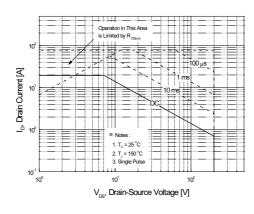


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



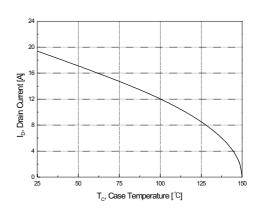


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

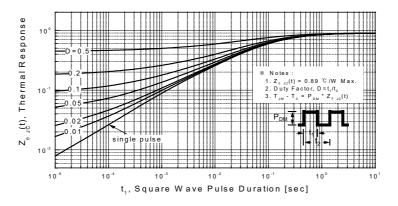
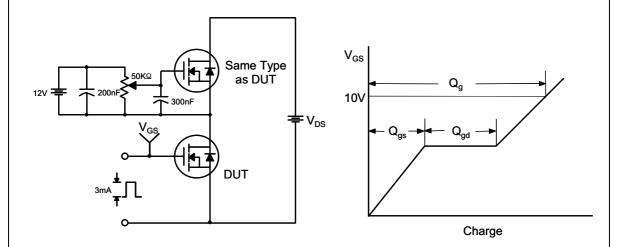
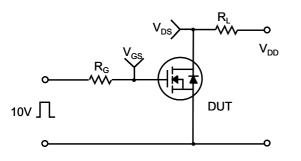


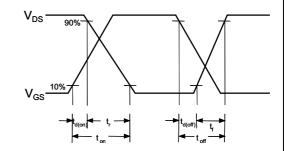
Figure 11. Transient Thermal Response Curve

Gate Charge Test Circuit & Waveform

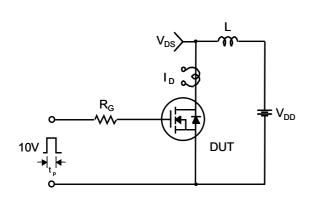


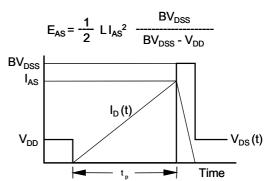
Resistive Switching Test Circuit & Waveforms



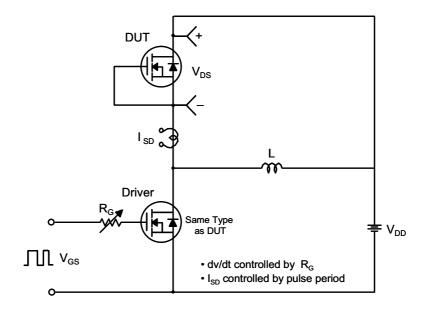


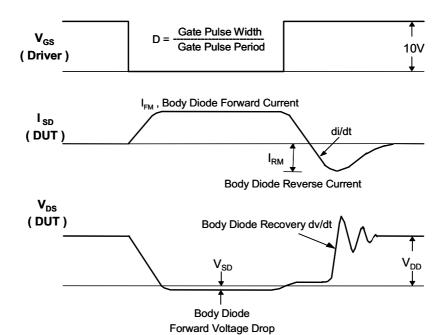
Unclamped Inductive Switching Test Circuit & Waveforms

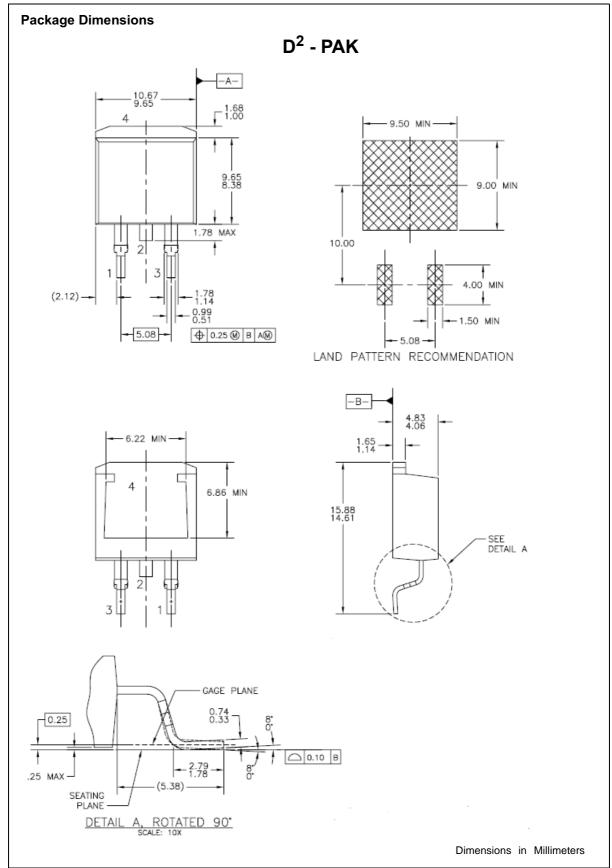




Peak Diode Recovery dv/dt Test Circuit & Waveforms







Package Dimensions (Continued) I² - PAK 10.29 Α 4.83 4.06 9.65 В 8.33 1.40 1.00 6.22 1.40 1.14 7.88 9.65 6.86 8.64 \oplus 2 1 3 B 3.96 2.80 (2.13) 14.73 2.79 2.03 12.70 1.78 B 0.64 0.33 2.54 0.90 0.64 5.08 → 0.254 AM B





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Rev. 137